

# PC3-8500 / PC3-10600 Un-buffered DDR3 SDRAM DIMM NT2GC64B8HC0NF

Based on DDR3-1066/1333 128Mx8 SDRAM C-Die

## Features

•Performance:

Speed Sort	PC3-8500	PC3-10600	Unit
	-BE	-CG	
DIMM CAS Latency	7	9	
fck – Clock Frequency	533	667	MHz
tck – Clock Cycle	1.875	1.5	ns
fDQ – DQ Burst Frequency	1066	1333	Mbps

- 240-Pin Dual In-Line Memory Module (UDIMM)
- 128Mx64 and 256Mx64 DDR3 Unbuffered DIMM based on 128Mx8 DDR3 SDRAM A-Die devices.
- Intended for 533MHz/667MHz applications
- Inputs and outputs are SSTL-15 compatible
- $V_{DD} = V_{DDQ} = 1.5V \pm 0.075V$
- SDRAMs have 8 internal banks for concurrent operation
- Differential clock inputs
- Data is read or written on both clock edges
- DRAM DLL aligns DQ and DQS transitions with clock transitions.
- Address and control signals are fully synchronous to positive clock edge
- Nominal and Dynamic On-Die Termination support
- Halogen free product
- Programmable Operation:
  - DIMM  $\overline{CAS}$  Latency: 6,7,8,9
  - Burst Type: Sequential or Interleave
  - Burst Length: BC4, BL8
  - Operation: Burst Read and Write
- Two different termination values (Rtt\_Nom & Rtt\_WR)
- 14/10/2 (row/column/rank) Addressing for 2GB
- Extended operating temperature range
- Auto Self-Refresh option
- Serial Presence Detect
- Gold contacts
- SDRAMs are in 78-ball BGA Package
- RoHS compliance

## Description

NT2GC64B8HC0NF is 240-Pin Double Data Rate 3 (DDR3) Synchronous DRAM Unbuffered Dual In-Line Memory Module (UDIMM), organized as two ranks of 256Mx64 (2GB) high-speed memory array. Modules use sixteen 128Mx8 (2GB) 78-ball BGA packaged devices. These DIMMs are manufactured using raw cards developed for broad industry use as reference designs. The use of these common design files minimizes electrical variation between suppliers. All NANYA DDR3 SDRAM DIMMs provide a high-performance, flexible 8-byte interface in a 5.25" long space-saving footprint.

The DIMM is intended for use in applications operating of 533MHz/667MHz clock speeds and achieves high-speed data transfer rates of 1066Mbps/1333Mbps. Prior to any access operation, the device  $\overline{CAS}$  latency and burst/length/operation type must be programmed into the DIMM by address inputs A0-A13 and I/O inputs BA0-BA2 using the mode register set cycle.

The DIMM uses serial presence-detect implemented via a serial EEPROM using a standard IIC protocol. The first 128 bytes of SPD data are programmed and locked during module assembly. The remaining 128 bytes are available for use by the customer.

**PC3-8500 / PC3-10600**  
**Un-buffered DDR3 SDRAM DIMM**  
**NT2GC64B8HC0NF**

**Ordering Information**

Part Number	Speed			Organization	Power	Leads	Note
NT2GC64B8HC0NF-BE	DDR3-1066	PC3-8500	533MHz (1.875ns @ CL = 7)	256Mx64	1.5V	Gold	
NT2GC64B8HC0NF-CG	DDR3-1333	PC3-10600	667MHz (1.5ns @ CL = 9)				

**Pin Description**

Pin Name	Description	Pin Name	Description
CK0, CK1	Clock Inputs, positive line	DQ0-DQ63	Data input/output
$\overline{\text{CK0}}, \overline{\text{CK1}}$	Clock Inputs, negative line	DQS0-DQS8	Data strobes
CKE0, CKE1	Clock Enable	$\overline{\text{DQS0}}-\overline{\text{DQS8}}$	Data strobes complement
$\overline{\text{RAS}}$	Row Address Strobe	DM0-DM8	Data Masks
$\overline{\text{CAS}}$	Column Address Strobe	$\overline{\text{EVENT}}$	Temperature event pin
WE	Write Enable	$\overline{\text{RESET}}$	Reset pin
$\overline{\text{S0}}, \overline{\text{S1}}$	Chip Selects	$V_{\text{REFDQ}}, V_{\text{REFCA}}$	Input/Output Reference
A0-A9, A11, A13	Address Inputs	$V_{\text{DDSPD}}$	SPD and Temp sensor power
A10/AP	Address Input/Auto-Precharge	SA0, SA1	Serial Presence Detect Address Inputs
A12/ $\overline{\text{BC}}$	Address Input/Burst Chop	Vtt	Termination voltage
BA0-BA2	SDRAM Bank Address Inputs	$V_{\text{SS}}$	Ground
ODT0, ODT1	Active termination control lines	$V_{\text{DD}}$	Core and I/O power
SCL	Serial Presence Detect Clock Input	NC	No Connect
SDA	Serial Presence Detect Data input/output		

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**DDR3 SDRAM Pin Assignment**

Pin	Front	Pin	Back	Pin	Front	Pin	Back	Pin	Front	Pin	Back	Pin	Front	Pin	Back
1	V <sub>REFDQ</sub>	121	V <sub>SS</sub>	31	DQ25	151	V <sub>SS</sub>	61	A2	181	A1	91	DQ41	211	V <sub>SS</sub>
2	V <sub>SS</sub>	122	DQ4	32	V <sub>SS</sub>	152	DM3	62	V <sub>DD</sub>	182	V <sub>DD</sub>	92	V <sub>SS</sub>	212	DM5
3	DQ0	123	DQ5	33	$\overline{\text{DQS}}3$	153	NC	63	CK1/NC	183	V <sub>DD</sub>	93	$\overline{\text{DQS}}5$	213	NC
4	DQ1	124	V <sub>SS</sub>	34	DQS3	154	V <sub>SS</sub>	64	$\overline{\text{CK}}1/\text{NC}$	184	CK0	94	DQS5	214	V <sub>SS</sub>
5	V <sub>SS</sub>	125	DM0	35	V <sub>SS</sub>	155	DQ30	65	V <sub>DD</sub>	185	$\overline{\text{CK}}0$	95	V <sub>SS</sub>	215	DQ46
6	$\overline{\text{DQS}}0$	126	NC	36	DQ26	156	DQ31	66	V <sub>DD</sub>	186	V <sub>DD</sub>	96	DQ42	216	DQ47
7	DQS0	127	V <sub>SS</sub>	37	DQ27	157	V <sub>SS</sub>	67	V <sub>REFCA</sub>	187	$\overline{\text{EVENT}}$	97	DQ43	217	V <sub>SS</sub>
8	V <sub>SS</sub>	128	DQ6	38	V <sub>SS</sub>	158	NC	68	NC	188	A0	98	V <sub>SS</sub>	218	DQ52
9	DQ2	129	DQ7	39	NC	159	NC	69	V <sub>DD</sub>	189	V <sub>DD</sub>	99	DQ48	219	DQ53
10	DQ3	130	V <sub>SS</sub>	40	NC	160	V <sub>SS</sub>	70	A10/AP	190	BA1	100	DQ49	220	V <sub>SS</sub>
11	V <sub>SS</sub>	131	DQ12	41	V <sub>SS</sub>	161	DM8	71	BA0	191	V <sub>DD</sub>	101	V <sub>SS</sub>	221	DM6
12	DQ8	132	DQ13	42	$\overline{\text{DQS}}8$	162	NC	72	V <sub>DD</sub>	192	$\overline{\text{RAS}}$	102	$\overline{\text{DQS}}6$	222	NC
13	DQ9	133	V <sub>SS</sub>	43	DQS8	163	V <sub>SS</sub>	73	$\overline{\text{WE}}$	193	$\overline{\text{S}}0$	103	DQS6	223	V <sub>SS</sub>
14	V <sub>SS</sub>	134	DM1	44	V <sub>SS</sub>	164	NC	74	$\overline{\text{CAS}}$	194	V <sub>DD</sub>	104	V <sub>SS</sub>	224	DQ54
15	$\overline{\text{DQS}}1$	135	NC	45	NC	165	NC	75	V <sub>DD</sub>	195	ODT0	105	DQ50	225	DQ55
16	DQS1	136	V <sub>SS</sub>	46	NC	166	V <sub>SS</sub>	76	$\overline{\text{S}}1/\text{NC}$	196	A13	106	DQ51	226	V <sub>SS</sub>
17	V <sub>SS</sub>	137	DQ14	47	V <sub>SS</sub>	167	NC	77	ODT1/NC	197	V <sub>DD</sub>	107	V <sub>SS</sub>	227	DQ60
18	DQ10	138	DQ15	48	NC	168	$\overline{\text{RESET}}$	78	V <sub>DD</sub>	198	NC	108	DQ56	228	DQ61
19	DQ11	139	V <sub>SS</sub>	49	NC	169	CKE1/NC	79	NC	199	V <sub>SS</sub>	109	DQ57	229	V <sub>SS</sub>
20	V <sub>SS</sub>	140	DQ20	50	CKE0	170	V <sub>DD</sub>	80	V <sub>SS</sub>	200	DQ36	110	V <sub>SS</sub>	230	DM7
21	DQ16	141	DQ21	51	V <sub>DD</sub>	171	NC	81	DQ32	201	DQ37	111	$\overline{\text{DQS}}7$	231	NC
22	DQ17	142	V <sub>SS</sub>	52	BA2	172	NC	82	DQ33	202	V <sub>SS</sub>	112	DQS7	232	V <sub>SS</sub>
23	V <sub>SS</sub>	143	DM2	53	NC	173	V <sub>DD</sub>	83	V <sub>SS</sub>	203	DM4	113	V <sub>SS</sub>	233	DQ62
24	$\overline{\text{DQS}}2$	144	NC	54	V <sub>DD</sub>	174	A12/BC	84	$\overline{\text{DQS}}4$	204	NC	114	DQ58	234	DQ63
25	DQS2	145	V <sub>SS</sub>	55	A11	175	A9	85	DQS4	205	V <sub>SS</sub>	115	DQ59	235	V <sub>SS</sub>
26	V <sub>SS</sub>	146	DQ22	56	A7	176	V <sub>DD</sub>	86	V <sub>SS</sub>	206	DQ38	116	V <sub>SS</sub>	236	V <sub>DDSPD</sub>
27	DQ18	147	DQ23	57	V <sub>DD</sub>	177	A8	87	DQ34	207	DQ39	117	SA0	237	SA1
28	DQ19	148	V <sub>SS</sub>	58	A5	178	A6	88	DQ35	208	V <sub>SS</sub>	118	SCL	238	SDA
29	V <sub>SS</sub>	149	DQ28	59	A4	179	V <sub>DD</sub>	89	V <sub>SS</sub>	209	DQ44	119	SA2	239	V <sub>SS</sub>
30	DQ24	150	DQ29	60	V <sub>DD</sub>	180	A3	90	DQ40	210	DQ45	120	V <sub>TT</sub>	240	V <sub>TT</sub>

Note: CK1,  $\overline{\text{CK}}1$ , CKE1,  $\overline{\text{S}}1$  and ODT1 are for 2GB modules only.

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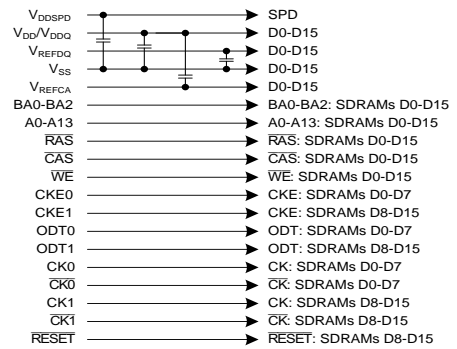
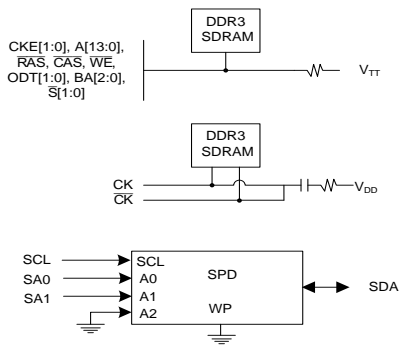
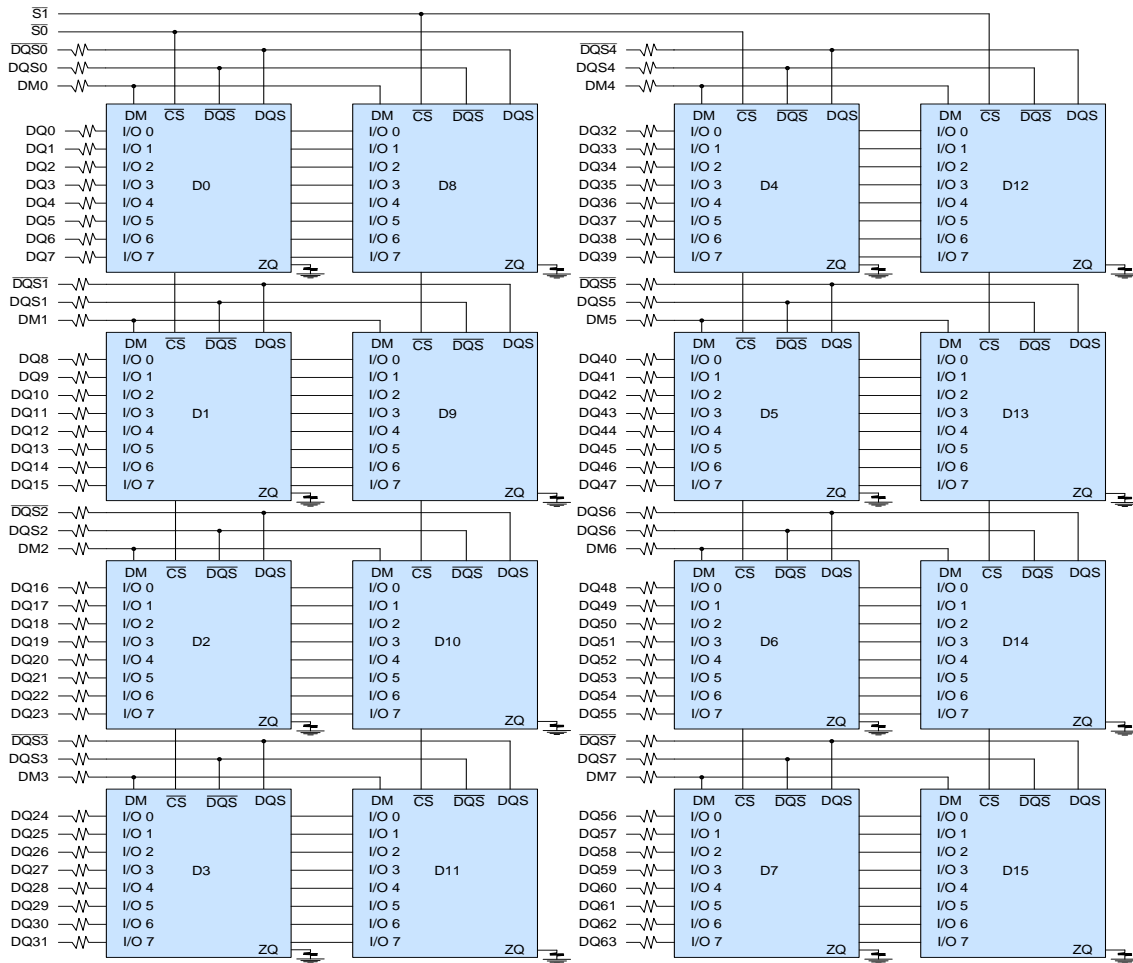
**Input/Output Functional Description**

Symbol	Type	Polarity	Function
CK0, CK1 $\overline{\text{CK0}}, \overline{\text{CK1}}$	Input	Cross point	The system clock inputs. All address and command lines are sampled on the cross point of the rising edge of CK and falling edge of $\overline{\text{CK}}$ . A Delay Locked Loop (DLL) circuit is driven from the clock inputs and output timing for read operations is synchronized to the input clock.
CKE0, CKE1	Input	Active High	Activates the DDR3 SDRAM CK signal when high and deactivates the CK signal when low. By deactivating the clocks, CKE low initiates the Power Down mode or the Self Refresh mode.
$\overline{\text{S0}}, \overline{\text{S1}}$	Input	Active Low	Enables the associated DDR3 SDRAM command decoder when low and disables the command decoder when high. When the command decoder is disabled, new commands are ignored but previous operations continue, Rank 0 is selected by $\overline{\text{S0}}$ ; Rank 1 is selected by $\overline{\text{S1}}$ .
$\overline{\text{RAS}}, \overline{\text{CAS}}, \overline{\text{WE}}$	Input	Active Low	When sampled at the positive rising edge of CK and falling edge of $\overline{\text{CK}}$ , signals $\overline{\text{RAS}}, \overline{\text{CAS}}, \overline{\text{WE}}$ define the operation to be executed by the SDRAM.
ODT0, ODT1	Input	Active High	Asserts on-die termination for DQ, DM, DQS, and $\overline{\text{DQS}}$ signals if enabled via the DDR3 SDRAM mode register.
DM0 – DM8	Input	Active High	The data write masks, associated with one data byte. In Write mode, DM operates as a byte mask by allowing input data to be written if it is low but blocks the write operation if it is high. In Read mode, DM lines have no effect.
DQS0 – DQS8 $\overline{\text{DQS0}} – \overline{\text{DQS8}}$	I/O	Cross point	The data strobes, associated with one data byte, sourced with data transfers. In Write mode, the data strobe is sourced by the controller and is centered in the data window. In Read mode, the data strobe is sourced by the DDR3 SDRAM and is sent at the leading edge of the data window. DQS signals are complements, and timing is relative to the cross point of respective DQS and $\overline{\text{DQS}}$ . If the module is to be operated in single ended strobe mode, all $\overline{\text{DQS}}$ signals must be tied on the system board to V <sub>SS</sub> and DDR3 SDRAM mode registers programmed appropriately.
BA0, BA1, BA2	Input	-	Selects which DDR3 SDRAM internal bank of four or eight is activated.
A0 – A9 A10/AP A11 A12/ $\overline{\text{BC}}$ A13	Input	-	During a Bank Activate command cycle, defines the row address when sampled at the cross point of the rising edge of CK and falling edge of $\overline{\text{CK}}$ . During a Read or Write command cycle, defines the column address when sampled at the cross point of the rising edge of CK and falling edge of $\overline{\text{CK}}$ . In addition to the column address, AP is used to invoke autoprecharge operation at the end of the burst read or write cycle. If AP is high, autoprecharge is selected and BA0-BAn defines the bank to be precharged. If AP is low, autoprecharge is disabled. During a Precharge command cycle, AP is used in conjunction with BA0-BAn to control which bank(s) to precharge. If AP is high, all banks will be precharged regardless of the state of BA0-BAn inputs. If AP is low, then BA0-BAn are used to define which bank to precharge.
DQ0 – DQ63	Input	-	Data Input/Output pins.
V <sub>DD</sub> , V <sub>DDSPD</sub> , V <sub>SS</sub>	Supply	-	Power supplies for core, I/O, Serial Presence Detect, Temp sensor, and ground for the module.
V <sub>REFDQ</sub> , V <sub>REFCA</sub>	Supply	-	Reference voltage for SSTL15 inputs
SDA	I/O	-	This is a bidirectional pin used to transfer data into or out of the SPD EEPROM and temp sensor. A resistor must be connected from the SDA bus line to V <sub>DDSPD</sub> on the system planar to act as a pull up.
SCL	Input	-	This signal is used to clock data into and out of the SPD EEPROM and Temp sensor.
SA0 – SA2	Input	-	Address pins used to select the Serial Presence Detect and Temp sensor base address.
$\overline{\text{EVENT}}$	Output	-	The $\overline{\text{EVENT}}$ pin is reserved for use to flag critical module temperature.
$\overline{\text{RESET}}$	Input	-	This signal resets the DDR3 SDRAM

**PC3-8500 / PC3-10600**  
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**Functional Block Diagram**

[2GB – 2 Ranks, 128Mx8 DDR3 SDRAMs]



- Notes :**
1. DQ-to-I/O wiring is shown as recommended but may be changed.
  2. DQ/DQS/DQS/ODT/DM/CKE/S relationships must be maintained as shown.
  3. For each DRAM, a unique ZQ resistor is connected to ground. The ZQ resistor is 240Ω ±1%.
  4. One SPD exists per module.

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**Serial Presence Detect (Part 1 of 2) [2GB – 2 Ranks, 128Mx8 DDR3 SDRAMs]**

Byte	Description	SPD Entry Value		Serial PD Data Entry (Hex.)	
		-BE	-CG	-BE	-CG
0	CRC range, EEPROM bytes, bytes used	CRC Covers Bytes: 0~116, Total SPD Bytes: 256, SPD Bytes Used: 176,	CRC Covers Bytes: 0~116, Total SPD Bytes: 256, SPD Bytes Used: 176,	92	92
1	SPD revision	Revision 1.0	Revision 1.0	10	10
2	DRAM device type	DDR3 SDRAM	DDR3 SDRAM	0B	0B
3	Module type (form factor)	UDIMM	UDIMM	02	02
4	SDRAM Device density and banks	8 banks, 1Gb	8 banks, 1Gb	02	02
5	SDRAM device row and column count	14 rows, 10 columns	14 rows, 10 columns	11	11
6	Module minimum nominal voltage	1.5 V	1.5 V	00	00
7	Module ranks and device DQ count	2 ranks, 8 bits	2 ranks, 8 bits	09	09
8	ECC tag and module memory Bus width	Non ECC, 64bits	Non ECC, 64bits	03	03
9	Fine timebase dividend/divisor (in ps)	2.5ps	2.5ps	52	52
10	Medium timebase dividend	1ns	1ns	01	01
11	Medium timebase divisor	8ns	8ns	08	08
12	Minimum SDRAM cycle time (tCKmin)	1.875ns	1.5ns	0F	0C
13	Reserved	Undefined	Undefined	00	00
14	CAS latencies supported	6,7,8	6,7,8,9	1C	3C
15	CAS latencies supported	Undefined	Undefined	00	00
16	Minimum CAS latency time (tAamin)	13.125ns	13.125ns	69	69
17	Minimum write recovery time (tWRmin)	15ns	15ns	78	78
18	Minimum $\overline{\text{CAS}}$ -to- $\overline{\text{CAS}}$ delay (tRCDmin)	13.125ns	13.125ns	69	69
19	Minimum Row Active to Row Active delay (tRRDmin)	7.5ns	6ns	3C	30
20	Minimum row Precharge delay (tRPmin)	13.125ns	13.125ns	69	69
21	Upper nibble for tRAS and tRC	1,1	1,1	11	11
22	Minimum Active-to-Precharge delay (tRASmin)	37.5ns	36ns	2C	20
23	Minimum Active-to-Active/Refresh delay (tRCmin)	50.625ns	49.125ns	95	89
24	Minimum refresh recovery delay (tRFCmin) LSB	(Combo bytes 24,25)	(Combo bytes 24,25)	70	70
25	Minimum refresh recovery delay (tRFCmin) MSB	110ns	110ns	03	03
26	Minimum internal Write-to-Read command delay (tWTRmin)	7.5ns	7.5ns	3C	3C
27	Minimum internal Read-to-Precharge command delay (tRTPmin)	7.5ns	7.5ns	3C	3C
28	Minimum four active window delay (tFAWmin) LSB	(Combo byte 28, 29)	(Combo byte 28, 29)	01	00
29	Minimum four active window delay (tFAWmin) MSB	37.5ns	30ns	2C	F0
30	SDRAM device output drivers supported	RZQ / 7, DLL-Off Mode Support,	RZQ / 7, DLL-Off Mode Support,	82	82
31	SDRAM device thermal and refresh options	Extended Temperature Range, ASR,	Extended Temperature Range, ASR,	05	05
32	Module thermal sensor	Non Thermal Sensor Support	Non Thermal Sensor Support	00	00
33	SDRAM device type	Standard Monolithic Device	Standard Monolithic Device	00	00
34-59	Reserved	Undefined	Undefined	--	--
60	Module height (nominal)	29 < height ≤ 30 mm	29 < height ≤ 30 mm	0F	0F
61	Module thickness (Max)	Back: 1 < thickness ≤ 2 mm, Front: 1 < thickness ≤ 2 mm,	Back: 1 < thickness ≤ 2 mm, Front: 1 < thickness ≤ 2 mm,	11	11
62	Raw Card ID reference	Raw Card B	Raw Card B	01	01
63	DRAM address mapping edge connector	Undefined	Undefined	01	01
64-116	Reserved	Undefined	Undefined	--	--
117-118	Module manufacture ID	Nanya Technology	Nanya Technology	830B	830B
119-125	Module information	Undefined	Undefined	--	--
126-127	CRC	Calculated Value	Calculated Value	4408	06A1

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**Serial Presence Detect (Part 2 of 2) [2GB – 2 Ranks, 128Mx8 DDR3 SDRAMs]**

Byte	Description	SPD Entry Value		Serial PD Data Entry (Hex.)	
		-BE	-CG	-BE	-CG
128-145	Module part number	ASCII values	ASCII values	--	--
146	Module die revision	Undefined	Undefined	00	00
147	Module PCB revision	Undefined	Undefined	00	00
148-149	DRAM device manufacturer ID	Nanya Technology	Nanya Technology	830B	830B
150-175	Manufacturer reserved	Undefined	Undefined	--	--
176-255	Customer reserved	Undefined	Undefined	--	--

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**Environmental Requirements**

Symbol	Parameter	Rating	Units	Note
T <sub>OPR</sub>	Module Operating Temperature Range (ambient)	0 to 55	°C	3
H <sub>OPR</sub>	Operating Humidity (relative)	10 to 90	%	1
T <sub>STG</sub>	Storage Temperature (Plastic)	-55 to 100	°C	1
H <sub>STG</sub>	Storage Humidity (without condensation)	5 to 95	%	1
P <sub>BAR</sub>	Barometric Pressure (operating & storage)	105 to 69	K Pascal	1, 2

**Note:**

- Stresses greater than those listed may cause permanent damage to the device. This is a stress rating only and device functional operation at or above the conditions indicated is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- Up to 9850 ft.
- The component maximum case temperature shall not exceed the value specified in the component spec.

**Absolute Maximum DC Ratings**

Symbol	Parameter	Rating	Units	Note
V <sub>DD</sub>	Voltage on VDD pins relative to Vss	-0.4 V ~ 1.975 V	V	1, 3
V <sub>DDQ</sub>	Voltage on VDDQ pins relative to Vss	-0.4 V ~ 1.975 V	V	1, 3
V <sub>IN</sub> , V <sub>OUT</sub>	Voltage on I/O pins relative to Vss	-0.4 V ~ 1.975 V	V	1
T <sub>STG</sub>	Storage Temperature	-55 to +100	°C	1, 2

**Note:**

- Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability
- Storage Temperature is the case surface temperature on the center/top side of the DRAM. For the measurement conditions, please refer to JESD51-2 standard.
- VDD and VDDQ must be within 300 mV of each other at all times; and VREF must be not greater

**Operating temperature Conditions**

Symbol	Parameter	Rating	Units	Note
T <sub>OPER</sub>	Normal Operating Temperature Range	0 to 85	°C	1, 2
	Extended Temperature Range	85 to 95	°C	1, 3

**Note:**

- Operating Temperature TOPER is the case surface temperature on the center / top side of the DRAM. For measurement conditions, please refer to the JEDEC document JEDEC document JEDEC51-2.
- The Normal Temperature Range specifies the temperatures where all DRAM specifications will be supported. During operation, the DRAM case temperature must be maintained between 0 to 85 °C under all operating conditions
- Some applications require operation of the DRAM in the Extended Temperature Range between 85 °C and 95 °C case temperature. Full specifications are supported in this range, but the following additional conditions apply:
  - Refresh commands must be doubled in frequency, therefore reducing the Refresh interval tREFI to 3.9 μs. It is also possible to specify a component with 1X refresh (tREFI to 7.8μs) in the Extended Temperature Range. Please refer to supplier data sheet and/or the DIMM SPD for option availability.
  - If Self-Refresh operation is required in the Extended Temperature Range, then it is mandatory to either use the Manual Self-Refresh mode with Extended Temperature Range capability (MR2 A6 = 0b and MR2 A7 = 1b) or enable the optional Auto Self-Refresh mode (MR2 A6 = 1b and MR2 A7 = 0b). Please refer to the supplier data sheet and/or the DIMM SPD for Auto Self-Refresh option availability, Extended Temperature Range support and tREFI requirements in the Extended Temperature Range.

**DC Electrical Characteristics and Operating Conditions**

Symbol	Parameter	Min	Typ	Max	Units	Notes
V <sub>DD</sub>	Supply Voltage	1.425	1.5	1.575	V	1,2
V <sub>DDQ</sub>	Output Supply Voltage	1.425	1.5	1.575	V	1,2

**Note:**

- Under all conditions VDDQ must be less than or equal to VDD.
- VDDQ tracks with VDD. AC parameters are measured with VDD and VDDQ tied together.



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**Single-Ended AC and DC Input Levels for Command and Address**

Symbol	Parameter	DDR3-1066 (-BE)		DDR3-1333 (-CG)		Units	Note
		Min.	Max.	Min.	Max.		
VIH.CA(DC)	DC Input Logic High	Vref + 0.100	VDD	Vref + 0.100	VDD	V	1
VIL.CA(DC)	DC Input Logic Low	VSS	Vref - 0.100	VSS	Vref - 0.100	V	1
VIH.CA(AC)	AC Input Logic High	Vref + 0.175	Note 2	Vref + 0.175	Note 2	V	1, 2
VIL.CA(AC)	AC Input Logic Low	Note 2	Vref - 0.175	Note 2	Vref - 0.175	V	1, 2
VIH.CA(AC150)	AC Input Logic High	Vref + 0.150	Note 2	Vref + 0.150	Note 2	V	1, 2
VIL.CA(AC150)	AC Input Logic Low	Note 2	Vref - 0.150	Note 2	Vref - 0.150	V	1, 2
V <sub>RefCA(DC)</sub>	Reference Voltage for ADD, CMD Inputs	0.49 x VDD	0.51 x VDD	0.49 x VDD	0.51 x VDD	V	3, 4

**Note:**

1. For input only pins except RESET#. Vref = VrefCA(DC).
2. See "Overshoot and Undershoot Specifications" in the device datasheet.
3. The ac peak noise on VRef may not allow VRef to deviate from VRefDQ(DC) by more than +/-1% VDD (for reference: approx. +/- 15 mV).
4. For reference: approx. VDD/2 +/- 15 mV.

**Single-Ended AC and DC Input Levels for DQ and DM**

Symbol	Parameter	DDR3-1066 (-BE)		DDR3-1333 (-CG)		Units	Note
		Min.	Max.	Min.	Max.		
VIH.DQ(DC)	DC Input Logic High	Vref + 0.100	VDD	Vref + 0.100	VDD	V	1
VIL.DQ(DC)	DC Input Logic Low	VSS	Vref - 0.100	VSS	Vref - 0.100	V	1
VIH.DQ(AC175)	AC Input Logic High	Vref + 0.175	Note 2	Vref + 0.15	Note 2	V	1, 2, 5
VIL.DQ(AC175)	AC Input Logic Low	Note 2	Vref - 0.175	Note 2	Vref - 0.150	V	1, 2, 5
VIH.DQ(AC150)	AC Input Logic High	Vref + 0.150	Note 2	Vref + 0.15	Note 2	V	1, 2, 5
VIL.DQ(AC150)	AC Input Logic Low	Note 2	Vref - 0.150	Note 2	Vref - 0.150	V	1, 2, 5
V <sub>RefDQ(DC)</sub>	Reference Voltage for DQ, DM Inputs	0.49 x VDD	0.51 x VDD	0.49 x VDD	0.51 x VDD	V	3, 4

**Note:**

1. For input only pins except RESET#. Vref = VrefDQ(DC).
2. See "Overshoot and Undershoot Specifications" in the device datasheet.
3. The ac peak noise on VRef may not allow VRef to deviate from VRefDQ(DC) by more than +/-1% VDD (for reference: approx. +/- 15 mV).
4. For reference: approx. VDD/2 +/- 15 mV.
5. Single-ended swing requirement for DQS, DQS# is 350 mV (peak to peak). Differential swing requirement for DQS - DQS# is 700 mV (peak to peak).

**PC3-8500 / PC3-10600**  
**Un-buffered DDR3 SDRAM DIMM**  
**NT2GC64B8HC0NF**

**Operating, Standby, and Refresh Currents**

T<sub>CASE</sub> = 0 °C ~ 85 °C; V<sub>DDQ</sub> = V<sub>DD</sub> = 1.5V ± 0.075V [2GB – 2 Ranks, 128Mx8 DDR3 SDRAMs]

Symbol	Parameter/Condition	PC3-8500 (-BE)	PC3-10600 (-CG)	Unit
IDD0	Operating One Bank Active-Precharge Current	1364	1496	mA
IDD1	Operating One Bank Active-Read-Precharge Current	1540	1672	mA
IDD2P0	Precharge Power-Down Current Slow Exit	211	211	mA
IDD2P1	Precharge Power-Down Current Fast Exit	440	528	mA
IDD2Q	Precharge Quiet Standby Current	968	1056	mA
IDD2N	Precharge Standby Current	880	968	mA
IDD3P	Active Power-Down Current	528	616	mA
IDD3N	Active Standby Current	968	1056	mA
IDD4R	Operating Burst Read Current	1892	2288	mA
IDD4W	Operating Burst Write Current	1892	2200	mA
IDD5B	Burst Refresh Current	2420	2640	mA
IDD6	Self Refresh Current: Normal Temperature Range	176	176	mA
IDD7	Operating Bank Interleave Read Current	3916	4840	mA

**PC3-8500 / PC3-10600**  
**Un-buffered DDR3 SDRAM DIMM**  
**NT2GC64B8HC0NF**

**Standard Speed Bins**

Speed Bin		DDR3-1066 (-BE)		DDR3-1333 (-CG)		Unit
CL-nRCD-nRP		7-7-7		9-9-9		
Parameter	Symbol	min	max	min	max	
Internal read command to first data	tAA	13.125	20	13.5	20	ns
ACT to internal read or write delay	tRCD	13.125	-	13.5	-	ns
PRE command period	tRP	13.125	-	13.5	-	ns
ACT to ACT or REF command period	tRC	50.625	-	49.5	-	ns
ACT to PRE command period	tRAS	37.5	9*tREFI	36	9*tREFI	ns
CL	CWL					
6	5	tCK(avg)	2.5   3.3	2.5   3.3		ns
6	6	tCK(avg)	Reserved	Reserved		ns
6	7,8	tCK(avg)	Reserved	Reserved		ns
7	5	tCK(avg)	Reserved	Reserved		ns
7	6	tCK(avg)	1.875   <2.5	Reserved		ns
7	7,8	tCK(avg)	Reserved	Reserved		ns
8	5	tCK(avg)	Reserved	Reserved		ns
8	6	tCK(avg)	1.875   <2.5	1.875   <2.5		ns
8	7	tCK(avg)	Reserved	Reserved		ns
9	5,6	tCK(avg)	Reserved	Reserved		ns
9	7	tCK(avg)	Reserved	1.5   <1.875		ns
9	8	tCK(avg)	Reserved	Reserved		ns
Supported CL settings		6, 7, 8		6, 7, 8, 9		nCK
Supported CWL settings		5,6		5,6,7		nCK

**PC3-8500 / PC3-10600**  
**Un-buffered DDR3 SDRAM DIMM**  
**NT2GC64B8HC0NF**

**AC Timing Specifications for DDR3 SDRAM Devices Used on Module**

Symbol	Parameter	DDR3-1066 (-BE)		DDR3-1333 (-CG)		Unit
		min	max	min	max	
<b>Clock Timing</b>						
tCK(DLL_OF)	Minimum Clock Cycle Time (DLL off mode)	8	-	8	-	ns
tCK(avg)	Average Clock Period(Refer to "Standard Speed)					
tCH(avg)	Average high pulse width	0.47	0.53	0.47	0.53	tCK(avg)
tCL(avg)	Average low pulse width	0.47	0.53	0.47	0.53	tCK(avg)
tCK(abs)	Absolute Clock Period	tCK(avg)min + tJIT(per)min	tCK(avg)max + tJIT(per)max	tCK(avg)min + tJIT(per)min	tCK(avg)max + tJIT(per)max	ps
tCH(abs)	Absolute high pulse width	0.43	-	0.43	-	tCK(avg)
tCL(abs)	Absolute low pulse width	0.43	-	0.43	-	tCK(avg)
JIT(per)	Clock Period Jitter	-90	90	-80	80	ps
tJIT(per,lck)	Clock Period Jitter during DLL locking period	-80	80	-70	70	ps
tJIT(cc)	Cycle to Clcycle Period Jitter	180		160		ps
tJIT(cc,lck)	Cycle to Cycle Period Jitter	160		140		ps
tERR(2per)	Cumulative error accross 2 cycles	-132	132	-118	118	ps
tERR(3per)	Cumulative error accross 3 cycles	-157	157	-140	140	ps
tERR(4per)	Cumulative error accross 4cycles	-175	175	-155	155	ps
tERR(5per)	Cumulative error accross 5cycles	-188	188	-168	168	ps
tERR(6per)	Cumulative error accross 6 cycles	-200	200	-177	177	ps
tERR(7per)	Cumulative error accross 7 cycles	-209	209	-186	186	ps
tERR(8per)	Cumulative error accross 8 cycles	-217	217	-193	193	ps
tERR(9per)	Cumulative error accross 9 cycles	-224	224	-200	200	ps
tERR(10per)	Cumulative error accross 10 cycles	-231	231	-205	205	ps
tERR(11per)	Cumulative error accross 11 cycles	-237	237	-210	210	ps
tERR(12per)	Cumulative error accross 12 cycles	-242	242	-215	215	ps
tERR(nper)	Cumulative error accross n=13,14,...,49,50 cycles	tERR(npr)min = (1+ 0.68ln(n)) * tJIT(per)min	tERR(npr)max = (1+ 0.68ln(n)) * tJIT(per)max	tERR(npr)min = (1+ 0.68ln(n)) * tJIT(per)min	tERR(npr)max = (1+ 0.68ln(n)) * tJIT(per)max	ps
<b>Data Timing</b>						
tDQSQ	DQS, DQS to DQ skew per group, per access	-	150	-	125	ps
tQH	DQ output hold time from DQS, DQS	0.38	-	0.38	-	tCK(avg)
tLZ(DQ)	DQ low-impedence time from CK / CK	-600	300	-500	250	ps
tHZ(DQ)	DQ high-impedence time from CK / CK	-	300	-	250	ps
tDS(base)	Data Setup time to DQS, DQS referenced to Vih(ac)/ Vil(ac) levels	25		TBD		ps
tDH(base)	Data Hold time to DQS, DQS referenced to Vih(dc)/ Vil(dc) levels	100		TBD		ps
<b>Data Strobe Timing</b>						
tRPRE	DQS, DQS differential READ Preamble	0.9	Note 19	0.9	Note 19	tCK(avg)
tRPST	DQS, DQS differential READ Postamble	0.3	Note 11	0.3	Note 11	tCK(avg)
tQSH	DQS, DQS differential output high time	0.38	-	0.4	-	tCK(avg)
tQSL	DQS, DQS differential output low time	0.38	-	0.4	-	tCK(avg)
tWPRE	DQS, DQS differential WRITE Preamble	0.9	-	0.9	-	tCK(avg)
tWPST	DQS, DQS differential WRITE Postamble	0.3	-	0.3	-	tCK(avg)
tDQSCK	DQS, DQS rising edge output access time from rising CK, CK	-300	300	-255	255	ps
tLZ(DQS)	DQS, DQS low-impedance time (Referenced from RL+BL/2)	-600	300	-500	250	ps
tHZ(DQS)	DQS, DQS high-impedance time (Referenced from RL+BL/2)	-	300	-	250	ps
tDQSL	DQS, DQS differential input low pulse width	0.4	0.6	0.4	0.6	tCK(avg)
tDQSH	DQS, DQS differential input high pulse width	0.4	0.6	0.4	0.6	tCK(avg)
tDQSS	DQS, DQS rising edge to CK, CK rising edge	-0.25	0.25	-0.25	0.25	tCK(avg)
tDSS	DQS, DQS falling edge setup time to CK, CK rising edge	0.2	-	0.2	-	tCK(avg)
tDSH	DQS, DQS falling edge hold time to CK, CK rising	0.2	-	0.2	-	tCK(avg)

**PC3-8500 / PC3-10600**  
**Un-buffered DDR3 SDRAM DIMM**  
**NT2GC64B8HCONF**

Symbol	Parameter	DDR3-1066 (-BE/-BF)		DDR3-1333 (-CG)		Unit
		min	max	min	max	
<b>Command and Address Timing</b>						
tDLLK	DLL Locking time	512	-	512	-	nCK
tRTP	Internal READ command to PRECHARGE Command delay	max(4nCK, 7.5ns)	-	max(4nCK, 7.5ns)	-	
tWTR	Delay from start of internal write transaction to internal read command	max(4nCK, 7.5ns)	-	max(4nCK, 7.5ns)	-	
tWR	WRITE recovery time	15	-	15	-	ns
tMRD	Mode Register Set command cycle time	4	-	4	-	nCK
tMOD	Mode Register Set command update delay	max(12nCK, 15ns)	-	max(12nCK, 15ns)	-	
tCCD	CAS to CAS command delay	4	-	4	-	nCK
tDAL	Auto Precharge write recovery + precharge time	WR + roundup (tRP/tCK(avg))		WR + roundup (tRP/tCK(avg))		nCK
tMPRR	End of MPR Read burst to MSR for MPR (exit)	1	-			nCK
tRAS	ACTIVE to PRECHARGE command period Refer to "Standard Speed Bins"					
tRRD	ACTIVE to ACTIVE command period (1k page size -x4/x8)	max(4nCK, 7.5ns)	-	max(4nCK, 6ns)	-	
tRRD	ACTIVE to ACTIVE command period (2k page size -x16)	max(4nCK, 10ns)	-	max(4nCK, 7.5ns)	-	
tFAW	Four activate window (1k page size - x4/x8)	37.5	-	30	0	ns
tFAW	Four activate window (2k page size - x16)	50	-	45	0	ns
tIS(base)	Command and Address setup time to CK, CK referenced Vih(ac) / Vil(ac) levels	125	-	65	-	ps
tIH(base)	Command and Address hold time from CK, CK referenced Vih(ac) / Vil(ac) levels	200	-	140	-	ps
tIS(base) AC150	Command and Address setup time to CK, CK referenced to Vih(ac) / Vil(ac) levels	-	-	65+125	-	ps
<b>Calibration Timing</b>						
tZQinit	Power-up and RESET calibration time	512	-	512	-	nCK
tZQoper	Normal operation Full calibration time	256	-	256	-	nCK
tZQCS	normal operation Short calibration time	64	-	64	-	nCK
<b>Reset Timing</b>						
tXPR	Exit Reset from CKE HIGH to a valid command	max(5nCK, tRFC(min) +10ns)	-	max(5nCK, tRFC(min) +10ns)	-	
<b>Self Refresh Timings</b>						
tXS	Exit Self Refresh to Commands not requiring a locked DLL	max(5nCK, tRFC(min) +10ns)	-	max(5nCK, tRFC(min) +10ns)	-	
tXSDLL	Exit Self Refresh to Commands requiring a locked	tDLLK(min)	-	tDLLK(min)	-	nCK
tCKESR	Minimum CKE low width for Self Refresh entry to exit timing	tCKE(min)+1nCK	-	tCKE(min)+1nCK	-	
tCKSRE	Valid Clock Requirement after Self Refresh Entry (SRE) or Power Down Entry (PDE)	max(5nCK, 10ns)	-	max(5nCK, 10ns)	-	
tCKSRX	Valid Clock Requirement before Self Refresh Exit (SRX) or Power-Down Exit (PDX) or Reset Exit	max(5nCK, 10ns)	-	max(5nCK, 10ns)	-	
<b>Power Down Timings</b>						
tXP	Exit Power Down with DLL on to any valid command; Exit Precharge Power Down with DLL frozen to commands not requiring a locked DLL	max(3nCK, 7.5ns)	-	max(3nCK, 6ns)	-	
tXPDLL	Exit Precharge Power Down with DLL frozen to commands requiring a locked DLL	max(10nCK, 24ns)	-	max(10nCK, 24ns)	-	
tCKE	CKE minimm pulse width	max(3nCK, 5.625ns)	-	max(3nCK, 5.625ns)	-	
tCPDED	Command Pass disable delay	1	-	1	-	nCK
tPD	Power Down Entry to Exit Timing	tCKE(min)	9tREFI	tCKE(min)	9tREFI	
tACTPDEN	Timing of ACT command to Power Down entry	1	-	1	-	nCK
tPRPDEN	Timing of PRE or PREA command to Power Down	1	-	1	-	nCK
tRDPDEN	Timing of RD/RDA command to Power Down entry	RL + 4 + 1	-	RL + 4 + 1	-	nCK

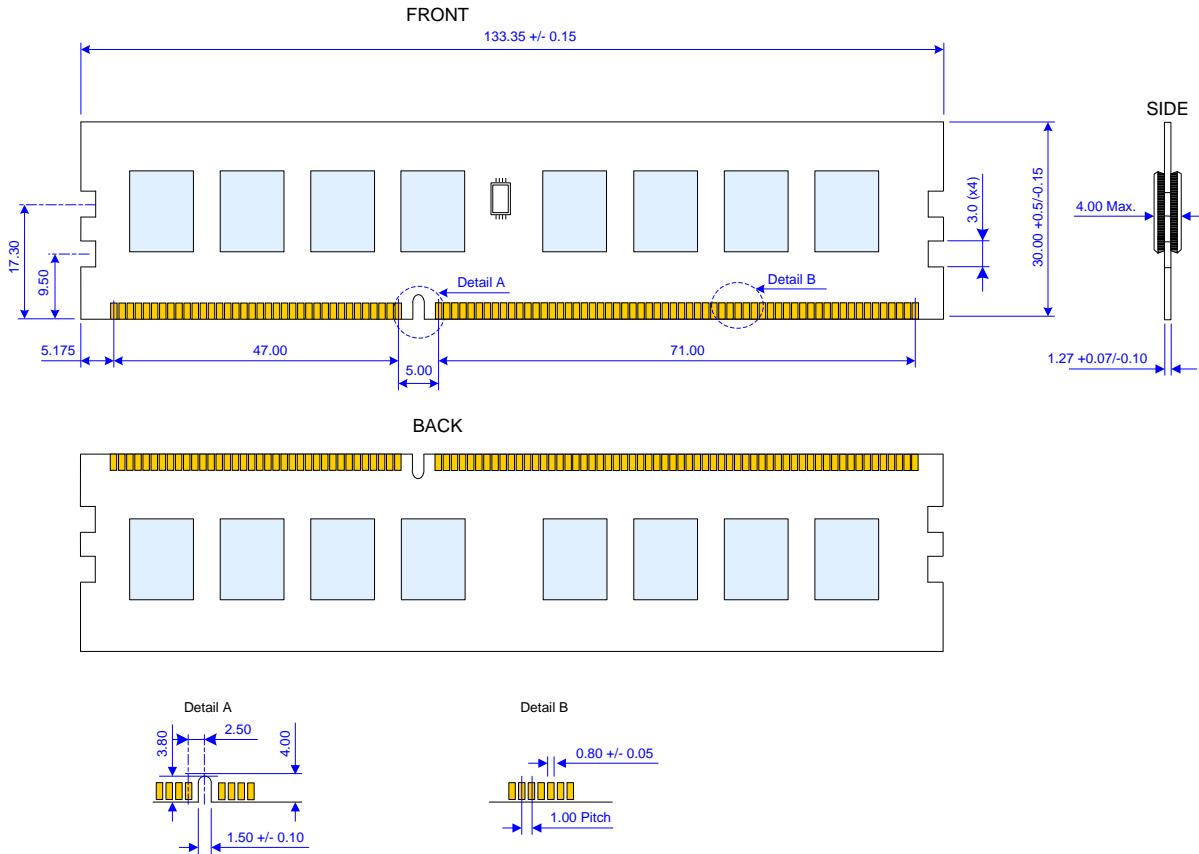
**PC3-8500 / PC3-10600**  
**Un-buffered DDR3 SDRAM DIMM**  
**NT2GC64B8HC0NF**

Symbol	Parameter	DDR3-1066 (-BE)		DDR3-1333 (-CG)		Unit
		min	max	min	max	
<b>Command and Address Timing</b>						
tDLLK	DLL Locking time	512	-	512	-	nCK
tRTP	Internal READ command to PRECHARGE Command delay	max(4nCK, 7.5ns)	-	max(4nCK, 7.5ns)	-	
tWTR	Delay from start of internal write transaction to internal read command	max(4nCK, 7.5ns)	-	max(4nCK, 7.5ns)	-	
tWR	WRITE recovery time	15	-	15	-	ns
tMRD	Mode Register Set command cycle time	4	-	4	-	nCK
tMOD	Mode Register Set command update delay	max(12nCK, 15ns)	-	max(12nCK, 15ns)	-	
tCCD	CAS to CAS command delay	4	-	4	-	nCK
tDAL	Auto Precharge write recovery + precharge time	WR + roundup (tRP/tCK(avg))		WR + roundup (tRP/tCK(avg))		nCK
tMPRR	End of MPR Read burst to MSR for MPR (exit)	1	-			nCK
tRAS	ACTIVE to PRECHARGE command period Refer to "Standard Speed Bins"					
tRRD	ACTIVE to ACTIVE command period (1k page size -x4/x8)	max(4nCK, 7.5ns)	-	max(4nCK, 6ns)	-	
tRRD	ACTIVE to ACTIVE command period (2k page size -x16)	max(4nCK, 10ns)	-	max(4nCK, 7.5ns)	-	
tFAW	Four activate window (1k page size - x4/x8)	37.5	-	30	0	ns
tFAW	Four activate window (2k page size - x16)	50	-	45	0	ns
tIS(base)	Command and Address setup time to CK, CK referenced Vih(ac) / Vil(ac) levels	125	-	65	-	ps
tIH(base)	Command and Address hold time from CK, CK referenced Vih(ac) / Vil(ac) levels	200	-	140	-	ps
tIS(base) AC150	Command and Address setup time to CK, CK referenced to Vih(ac) / Vil(ac) levels	-	-	65+125	-	ps
<b>Calibration Timing</b>						
tZQinit	Power-up and RESET calibration time	512	-	512	-	nCK
tZQoper	Normal operation Full calibration time	256	-	256	-	nCK
tZQCS	normal operation Short calibration time	64	-	64	-	nCK
<b>Reset Timing</b>						
tXPR	Exit Reset from CKE HIGH to a valid command	max(5nCK, tRFC(min) +10ns)	-	max(5nCK, tRFC(min) +10ns)	-	
<b>Self Refresh Timings</b>						
tXS	Exit Self Refresh to Commands not requiring a locked DLL	max(5nCK, tRFC(min) +10ns)	-	max(5nCK, tRFC(min) +10ns)	-	
tXSDLL	Exit Self Refresh to Commands requiring a locked DLL	tDLLK(min)	-	tDLLK(min)	-	nCK
tCKESR	Minimum CKE low width for Self Refresh entry to exit timing	tCKE(min)+1nCK	-	tCKE(min)+1nCK	-	
tCKSRE	Valid Clock Requirement after Self Refresh Entry (SRE) or Power Down Entry (PDE)	max(5nCK, 10ns)	-	max(5nCK, 10ns)	-	
tCKSRX	Valid Clock Requirement before Self Refresh Exit(SRX) or Power-Down Exit (PDX) or Reset Exit	max(5nCK, 10ns)	-	max(5nCK, 10ns)	-	
<b>Power Down Timings</b>						
tXP	Exit Power Down with DLL on to any valid command; Exit Precharge Power Down with DLL frozen to commands not requiring a locked DLL	max(3nCK, 7.5ns)	-	max(3nCK, 6ns)	-	
tXPDLL	Exit Precharge Power Down with DLL frozen to commands requiring a locked DLL	max(10nCK, 24ns)	-	max(10nCK, 24ns)	-	
tCKE	CKE minimum pulse width	max(3nCK, 5.625ns)	-	max(3nCK, 5.625ns)	-	
tCPDED	Command Pass disable delay	1	-	1	-	nCK
tPD	Power Down Entry to Exit Timing	tCKE(min)	9tREFI	tCKE(min)	9tREFI	
tACTPDEN	Timing of ACT command to Power Down entry	1	-	1	-	nCK
tPRPDEN	Timing of PRE or PREA command to Power Down entry	1	-	1	-	nCK
tRDPDEN	Timing of RD/RDA command to Power Down entry	RL + 4 + 1	-	RL + 4 + 1	-	nCK

**PC3-8500 / PC3-10600  
Un-buffered DDR3 SDRAM DIMM  
NT2GC64B8HC0NF**

**Package Dimensions**

[NT2GC64B8HC0NF, 2GB – 2 Ranks, 128Mx8 DDR3 SDRAMs]



Units: Millimeters

Note: Device position and scale are only for reference.

**Revision Log**

**REV 1.0**  
12/2009

**PC3-8500 / PC3-10600  
Un-buffered DDR3 SDRAM DIMM  
NT2GC64B8HC0NF**

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Rev	Date	Modification
0.1	10/2009	Preliminary Release
1.0	12/2009	Official Release

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